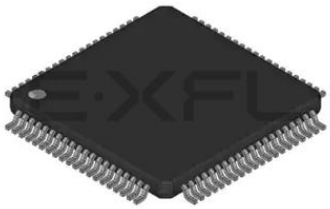
Infineon Technologies - XC2298H200F100LABKXUMA1 Datasheet



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Applications of "Embedded - Microcontrollers"

Details	
Product Status	Not For New Designs
Core Processor	C166SV2
Core Size	16/32-Bit
Speed	100MHz
Connectivity	CANbus, EBI/EMI, I²C, LINbus, SPI, SSC, UART/USART, USI
Peripherals	DMA, I²S, POR, PWM, WDT
Number of I/O	150
Program Memory Size	1.6MB (1.6M x 8)
Program Memory Type	FLASH
EEPROM Size	-
RAM Size	138K x 8
Voltage - Supply (Vcc/Vdd)	3V ~ 5.5V
Data Converters	A/D 30x10b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 125°C (TA)
Mounting Type	Surface Mount
Package / Case	176-LQFP Exposed Pad
Supplier Device Package	PG-LQFP-176-12
Purchase URL	https://www.e-xfl.com/product-detail/infineon-technologies/xc2298h200f100labkxuma1

16/32-Bit Single-Chip Microcontroller with 32-Bit Performance

XC229[89]H (XC2000 Family)

1 Summary of Features

For a quick overview and easy reference, the features of the XC229[89]H are summarized here.

- High-performance CPU with five-stage pipeline and MPU
  - 10 ns instruction cycle @ 100 MHz CPU clock (single-cycle execution)
  - One-cycle 32-bit addition and subtraction with 40-bit result
  - One-cycle multiplication (16 × 16 bit)
  - Background division (32 / 16 bit) in 21 cycles
  - One-cycle multiply-and-accumulate (MAC) instructions
  - Enhanced Boolean bit manipulation facilities
  - Zero-cycle jump execution
  - Additional instructions to support HLL and operating systems
  - Register-based design with multiple variable register banks
  - Fast context switching support with two additional local register banks
  - 16 Mbytes total linear address space for code and data
  - 1,024 Bytes on-chip special function register area (C166 Family compatible)
  - Integrated Memory Protection Unit (MPU)
- Interrupt system with 16 priority levels providing 112 interrupt nodes
  - Selectable external inputs for interrupt generation and wake-up
  - Fastest sample-rate 10 ns
- Eight-channel interrupt-driven single-cycle data transfer with Peripheral Event Controller (PEC), 24-bit pointers cover total address space
- Clock generation from internal or external clock sources, using on-chip PLL or prescaler
- Hardware CRC-Checker with Programmable Polynomial to Supervise On-Chip Memory Areas
- On-chip memory modules
  - 8 Kbytes on-chip stand-by RAM (SBRAM)
  - 2 Kbytes on-chip dual-port RAM (DPRAM)
  - 24 Kbytes on-chip data SRAM (DSRAM)
  - Up to 112 Kbytes on-chip program/data SRAM (PSRAM)
  - Up to 1,600 Kbytes on-chip program memory (Flash memory)
  - Memory content protection through Error Correction Code (ECC)

Table 6 Pin Definitions and Functions (cont'd)

Pin	Symbol	Ctrl.	Type	Function
100	P12.6	O0 / I	St/B	**Bit 6 of Port 12, General Purpose Input/Output**
	CC1_CC6	O1 / I	St/B	**CAPCOM1 CC6IO Capture Inp./ Compare Out.**
	U4C0_MCLKOUT	O2	St/B	**USIC4 Channel 0 Master Clock Output**
	U3C1_SELO2	O3	St/B	**USIC3 Channel 1 Select/Control 2 Output**
	RxDC3F	I	St/B	**CAN Node 3 Receive Data Input**
	CCU63_CCPOS1B	I	St/B	**CCU63 Position Input 1**
101	P0.2	O0 / I	St/B	**Bit 2 of Port 0, General Purpose Input/Output**
	U1C0_SCLKOUT	O1	St/B	**USIC1 Channel 0 Shift Clock Output**
	TxDC0	O2	St/B	**CAN Node 0 Transmit Data Output**
	CCU61_CC62	O3	St/B	**CCU61 Channel 2 Output**
	A2	OH	St/B	**External Bus Interface Address Line 2**
	U1C0_DX1B	I	St/B	**USIC1 Channel 0 Shift Clock Input**
	CCU61_CC62INA	I	St/B	**CCU61 Channel 2 Input**
102	P10.0	O0 / I	St/B	**Bit 0 of Port 10, General Purpose Input/Output**
	U0C1_DOUT	O1	St/B	**USIC0 Channel 1 Shift Data Output**
	CCU60_CC60	O2	St/B	**CCU60 Channel 0 Output**
	AD0	OH / IH	St/B	**External Bus Interface Address/Data Line 0**
	CCU60_CC60INA	I	St/B	**CCU60 Channel 0 Input**
	ESR1_2	I	St/B	**ESR1 Trigger Input 2**
	U0C0_DX0A	I	St/B	**USIC0 Channel 0 Shift Data Input**
	U0C1_DX0A	I	St/B	**USIC0 Channel 1 Shift Data Input**

Table 6 Pin Definitions and Functions (cont'd)

Pin	Symbol	Ctrl.	Type	Function
115	P2.10	O0 / I	St/B	**Bit 10 of Port 2, General Purpose Input/Output**
	U0C1_DOUT	O1	St/B	**USIC0 Channel 1 Shift Data Output**
	U0C0_SELO 3	O2	St/B	**USIC0 Channel 0 Select/Control 3 Output**
	CC2_CC23	O3 / I	St/B	**CAPCOM2 CC23IO Capture Inp./ Compare Out.**
	A23	OH	St/B	**External Bus Interface Address Line 23**
	U0C1_DX0E	I	St/B	**USIC0 Channel 1 Shift Data Input**
	CAPINA	I	St/B	**GPT12E Register CAPREL Capture Input**
	U3C1_DX0A	I	St/B	**USIC3 Channel 1 Shift Data Input**
116	P10.3	O0 / I	St/B	**Bit 3 of Port 10, General Purpose Input/Output**
	CCU60_COU T60	O2	St/B	**CCU60 Channel 0 Output**
	AD3	OH / IH	St/B	**External Bus Interface Address/Data Line 3**
	U0C0_DX2A	I	St/B	**USIC0 Channel 0 Shift Control Input**
	U0C1_DX2A	I	St/B	**USIC0 Channel 1 Shift Control Input**
	U3C0_DX0A	I	St/B	**USIC3 Channel 0 Shift Data Input**
117	P0.5	O0 / I	St/B	**Bit 5 of Port 0, General Purpose Input/Output**
	U1C1_SCLK OUT	O1	St/B	**USIC1 Channel 1 Shift Clock Output**
	U1C0_SELO 2	O2	St/B	**USIC1 Channel 0 Select/Control 2 Output**
	CCU61_COU T62	O3	St/B	**CCU61 Channel 2 Output**
	A5	OH	St/B	**External Bus Interface Address Line 5**
	U1C1_DX1A	I	St/B	**USIC1 Channel 1 Shift Clock Input**
	U1C0_DX1C	I	St/B	**USIC1 Channel 0 Shift Clock Input**
	RXDC3E	I	St/B	**CAN Node 3 Receive Data Input**
118	P12.2	O0 / I	St/B	**Bit 2 of Port 12, General Purpose Input/Output**
	CC1_CC2	O1 / I	St/B	**CAPCOM1 CC2IO Capture Inp./ Compare Out.**
	U4C0_DX1B	I	St/B	**USIC4 Channel 0 Shift Clock Input**

2.2 Identification Registers

The identification registers describe the current version of the XC229[89]H and of its modules.

Table 7 XC229[89]H Identification Registers

Short Name	Value	Address	Notes
SCU_IDMANUF	1820_H	$00'F07E_H$	
SCU_IDCHIP	4001_H	$00'F07C_H$	marking EES-AA or ES-AA
	4002_H	$00'F07C_H$	marking ES+AA, ES-AB or AB
SCU_IDMEM	$318F_H$	$00'F07A_H$	
SCU_IDPROG	1313_H	$00'F078_H$	
JTAG_ID	$0018'A083_H$	---	marking EES-AA or ES-AA
	$1018'A083_H$	---	marking ES+AA
	$2018'A083_H$	---	marking ES-AB or AB

3 Functional Description

The architecture of the XC229[89]H combines advantages of RISC, CISC, and DSP processors with an advanced peripheral subsystem in a well-balanced design. On-chip memory blocks allow the design of compact systems-on-silicon with maximum performance suited for computing, control, and communication.

The on-chip memory blocks (program code memory and SRAM, dual-port RAM, data SRAM) and the generic peripherals are connected to the CPU by separate high-speed buses. Another bus, the LXBus, connects additional on-chip resources and external resources. This bus structure enhances overall system performance by enabling the concurrent operation of several subsystems of the XC229[89]H.

The block diagram gives an overview of the on-chip components and the advanced internal bus structure of the XC229[89]H.

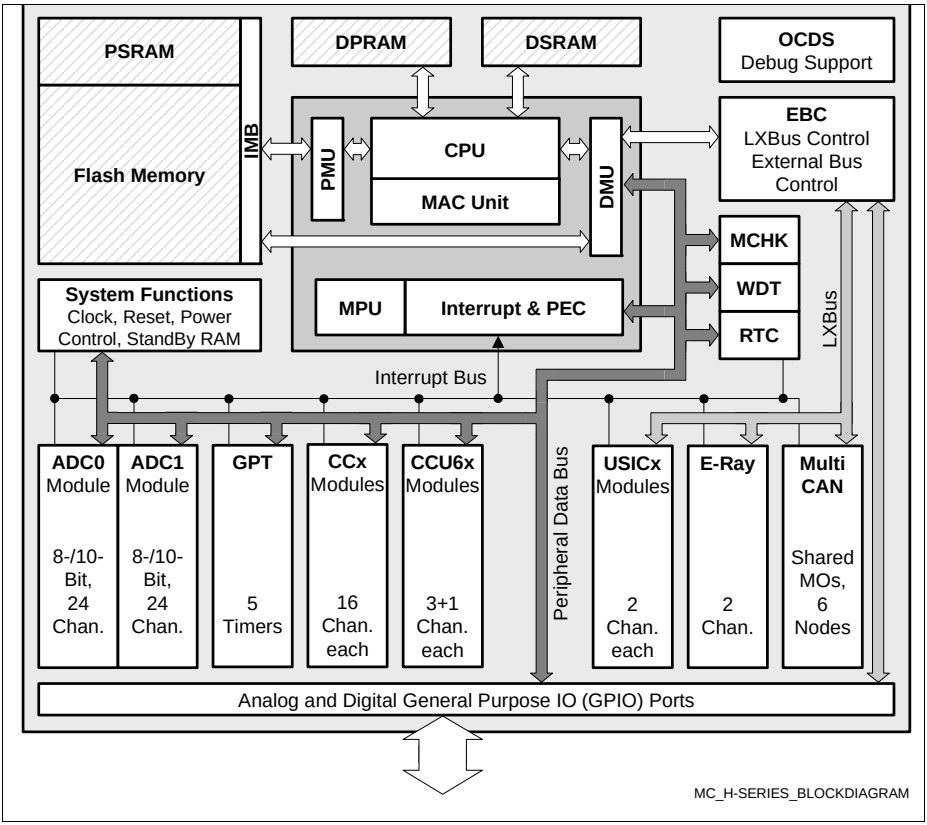

Figure 4 Block Diagram

3.4 Memory Protection Unit (MPU)

The XC229[89]H's Memory Protection Unit (MPU) protects user-specified memory areas from unauthorized read, write, or instruction fetch accesses. The MPU can protect the whole address space including the peripheral area. This completes established mechanisms such as the register security mechanism or stack overrun/underrun detection.

Four Protection Levels support flexible system programming where operating system, low level drivers, and applications run on separate levels. Each protection level permits different access restrictions for instructions and/or data.

Every access is checked (if the MPU is enabled) and an access violating the permission rules will be marked as invalid and leads to a protection trap.

A set of protection registers for each protection level specifies the address ranges and the access permissions. Applications requiring more than 4 protection levels can dynamically re-program the protection registers.

3.5 Memory Checker Module (MCHK)

The XC229[89]H's Memory Checker Module calculates a checksum (fractional polynomial division) on a block of data, often called Cyclic Redundancy Code (CRC). It is based on a 32-bit linear feedback shift register and may, therefore, also be used to generate pseudo-random numbers.

The Memory Checker Module is a 16-bit parallel input signature compression circuitry which enables error detection within a block of data stored in memory, registers, or communicated e.g. via serial communication lines. It reduces the probability of error masking due to repeated error patterns by calculating the signature of blocks of data.

The polynomial used for operation is configurable, so most of the commonly used polynomials may be used. Also, the block size for generating a CRC result is configurable via a local counter. An interrupt may be generated if testing the current data block reveals an error.

An autonomous CRC compare circuitry is included to enable redundant error detection, e.g. to enable higher safety integrity levels.

The Memory Checker Module provides enhanced fault detection (beyond parity or ECC) for data and instructions in volatile and non volatile memories. This is especially important for the safety and reliability of embedded systems.

3.13 Universal Serial Interface Channel Modules (USIC)

The XC229[89]H features the USIC modules USIC0, USIC1, USIC2, USIC3, USIC4. Each module provides two serial communication channels.

The Universal Serial Interface Channel (USIC) module is based on a generic data shift and data storage structure which is identical for all supported serial communication protocols. Each channel supports complete full-duplex operation with a basic data buffer structure (one transmit buffer and two receive buffer stages). In addition, the data handling software can use FIFOs.

The protocol part (generation of shift clock/data/control signals) is independent of the general part and is handled by protocol-specific preprocessors (PPPs).

The USIC's input/output lines are connected to pins by a pin routing unit. The inputs and outputs of each USIC channel can be assigned to different interface pins, providing great flexibility to the application software. All assignments can be made during runtime.

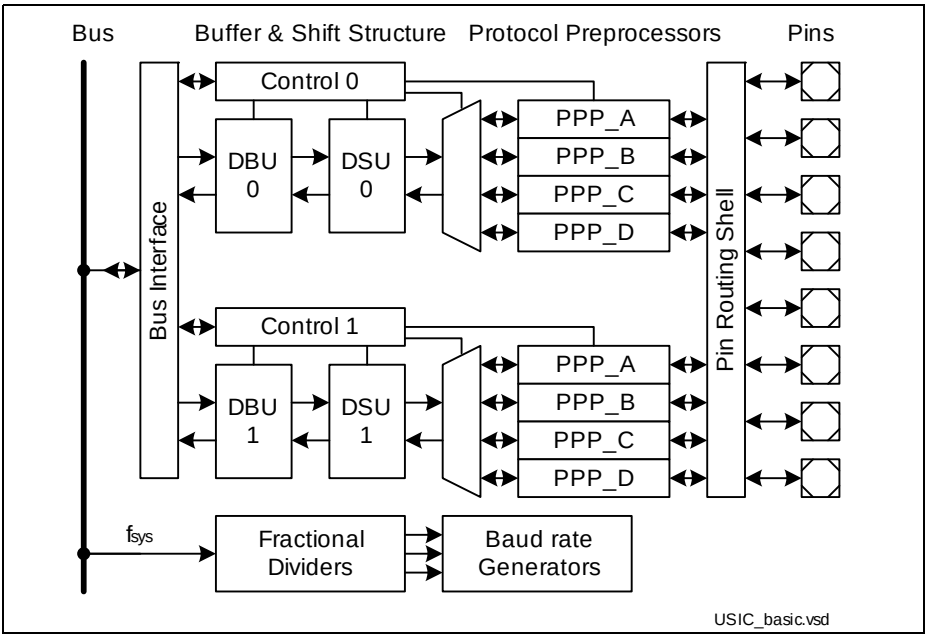

Figure 11 General Structure of a USIC Module

The regular structure of the USIC module brings the following advantages:

- Higher flexibility through configuration with same look-and-feel for data management
- Reduced complexity for low-level drivers serving different protocols
- Wide range of protocols with improved performances (baud rate, buffer handling)

3.16 System Timer

The System Timer consists of a programmable prescaler and two concatenated timers (10 bits and 6 bits). Both timers can generate interrupt requests. The clock source can be selected and the timers can also run during power reduction modes.

Therefore, the System Timer enables the software to maintain the current time for scheduling functions or for the implementation of a clock.

3.17 Watchdog Timer

The Watchdog Timer is one of the fail-safe mechanisms which have been implemented to prevent the controller from malfunctioning for longer periods of time.

The Watchdog Timer is always enabled after an application reset of the chip. It can be disabled and enabled at any time by executing the instructions DISWDT and ENWDT respectively. The software has to service the Watchdog Timer before it overflows. If this is not the case because of a hardware or software failure, the Watchdog Timer overflows, generating a prewarning interrupt and then a reset request.

The Watchdog Timer is a 16-bit timer clocked with the system clock divided by 16,384 or 256. The Watchdog Timer register is set to a prespecified reload value (stored in WDTREL) in order to allow further variation of the monitored time interval. Each time it is serviced by the application software, the Watchdog Timer is reloaded and the prescaler is cleared.

Time intervals between 3.2 µs and 13.4 s can be monitored (@ 80 MHz).

Time intervals between 2.56 µs and 10.71 s can be monitored (@ 100 MHz).

The default Watchdog Timer interval after power-up is 6.5 ms (@ 10 MHz).

3.18 Clock Generation

The Clock Generation Unit can generate the system clock signal f_{SYS} for the XC229[89]H from a number of external or internal clock sources:

- External clock signals with pad voltage or core voltage levels
- External crystal or resonator using the on-chip oscillator
- On-chip clock source for operation without crystal/resonator
- Wake-up clock (ultra-low-power) to further reduce power consumption

The programmable on-chip PLL with multiple prescalers generates a clock signal for maximum system performance from standard crystals, a clock input signal, or from the on-chip clock source. See also **Section 4.7.2**.

The Oscillator Watchdog (OWD) generates an interrupt if the crystal oscillator frequency falls below a certain limit or stops completely. In this case, the system can be supplied with an emergency clock to enable operation even after an external clock failure.

All available clock signals can be output on one of two selectable pins.

4.3.3 Power Consumption

The power consumed by the XC229[89]H depends on several factors such as supply voltage, operating frequency, active circuits, and operating temperature. The power consumption specified here consists of two components:

- The switching current I_S depends on the device activity
- The leakage current I_{LK} depends on the device temperature

To determine the actual power consumption, always both components, switching current I_S and leakage current I_{LK} must be added:

$I_{DDP} = I_S + I_{LK}$.

Note: The power consumption values are not subject to production test. They are verified by design/characterization.
To determine the total power consumption for dimensioning the external power supply, also the pad driver currents must be considered.

The given power consumption parameters and their values refer to specific operating conditions:

- **Active mode**:
  Regular operation, i.e. peripherals are active, code execution out of Flash.
- **Stopover mode**:
  Crystal oscillator and PLL stopped, Flash switched off, clock in domain DMP_1 stopped.
- **Standby mode**:
  Voltage domain DMP_1 switched off completely, power supply control switched off. DMP_M domain is supplied by ultra low power electronic voltage regulator (ULPEVR). The alternate regulator EVR_M is switched off.

Note: The maximum values cover the complete specified operating range of all manufactured devices.
The typical values refer to average devices under typical conditions, such as nominal supply voltage, room temperature, application-oriented activity.
After a power reset, the decoupling capacitors for V_{DDIM} and V_{DDI1} are charged with the maximum possible current.

For additional information, please refer to **Section 5.2**, **Thermal Considerations**.

Note: Operating Conditions apply.

Table 18 Switching Power Consumption

Parameter	Symbol	Values			Unit	Note / Test Condition
		Min.	Typ.	Max.		
Power supply current (active) with all peripherals active and EVVRs on[1]	I_{SACT_FR} CC	–	40 + 0.9 x f_{SYS}[2]	40 + 1.4 x f_{SYS}[2]	mA	power_mode= active ; voltage_range= both [3][4][5]
Power supply current in standby mode	I_{SSB} CC	–	95	200	µA	power_mode= standby ; voltage_range= lower [6]
		–	120	330	µA	power_mode= standby ; voltage_range= upper [6]
Power supply current in stopover mode, EVVRs on	I_{SSO} CC	–	1.4	4.0	mA	power_mode= stopover ; voltage_range= both [4]

1) If the FlexRay module clock (running @ 80 MHz) is turned off (KSCFG.MODEN=0) the value is reduced by 15 mA.

2) f_{SYS} in MHz

3) The pad supply voltage pins (V_{DDPB}) provide the input current for the on-chip EVVRs and the current consumed by the pin output drivers. A small current is consumed because the drivers input stages are switched. In Fast Startup Mode (with the Flash modules deactivated), the typical current is reduced to 3 + 0.6 x f_{SYS}.

4) Please consider the additional conditions described in section "Active Mode Power Supply Current".

5) The pad supply voltage has only a minor influence on this parameter.

6) These values are valid if the voltage validation circuits for V_{DDPB} (SWD) and V_{DDIM} (PVC_M) are off. Leaving SWD and PVC_M active adds another 90 µA.

Active Mode Power Supply Current

The actual power supply current in active mode not only depends on the system frequency but also on the configuration of the XC229[89]H's subsystem.

Besides the power consumed by the device logic the power supply pins also provide the current that flows through the pin output drivers.
A small current is consumed because the drivers' input stages are switched.

The IO power domains can be supplied separately. Power domain A (V_{DDPA}) supplies the A/D converters and Port 6. Power domain B (V_{DDPB}) supplies the on-chip EVVRs and all other ports.

Table 19 Leakage Power Consumption

Parameter	Symbol	Values			Unit	Note / Test Condition
		Min.	Typ.	Max.		
Leakage supply current (DMP_1 off)[1)2)]	I_{LK0} CC	–	20	35	µA	T_J= 25 °C
		–	115	330	µA	T_J= 85 °C
		–	270	880	µA	T_J= 125 °C
		–	420	1.445	µA	T_J= 150 °C
Leakage supply current (DMP_1 powered)[1)2)]	I_{LK1} CC	–	0.04	0.06	mA	T_J= 25 °C
		–	0.7	1.8	mA	T_J= 85 °C
		–	3.1	8.6	mA	T_J= 125 °C
		–	6.6	19.2	mA	T_J= 150 °C

1) The supply current caused by leakage depends mainly on the junction temperature and the supply voltage. The temperature difference between the junction temperature T_J and the ambient temperature T_A must be taken into account. As this fraction of the supply current does not depend on device activity, it must be added to other power consumption values.

2) All inputs (including pins configured as inputs) are set at 0 V to 0.1 V or at V_{DDP} - 0.1 V to V_{DDP} and all outputs (including pins configured as outputs) are disconnected.

Note: A fraction of the leakage current flows through domain DMP_A (pin V_{DDPA}). This current can be calculated as 7,000 $\times e^{-\alpha}$, with α = 5000 / (273 + 1.3 $\times T_J$). For T_J = 150°C, this results in a current of 160 µA.

The leakage power consumption can be calculated according to the following formulas:

$I_{LK0} = 500{,}000 \times e^{-\alpha}$ with $\alpha = 3000 / (273 + B \times T_J)$

Parameter B must be replaced by

- 1.0 for typical values
- 1.6 for maximum values

$I_{LK1} = 600{,}000 \times e^{-\alpha}$ with $\alpha = 5000 / (273 + B \times T_J)$

Parameter B must be replaced by

- 1.1 for typical values
- 1.4 for maximum values

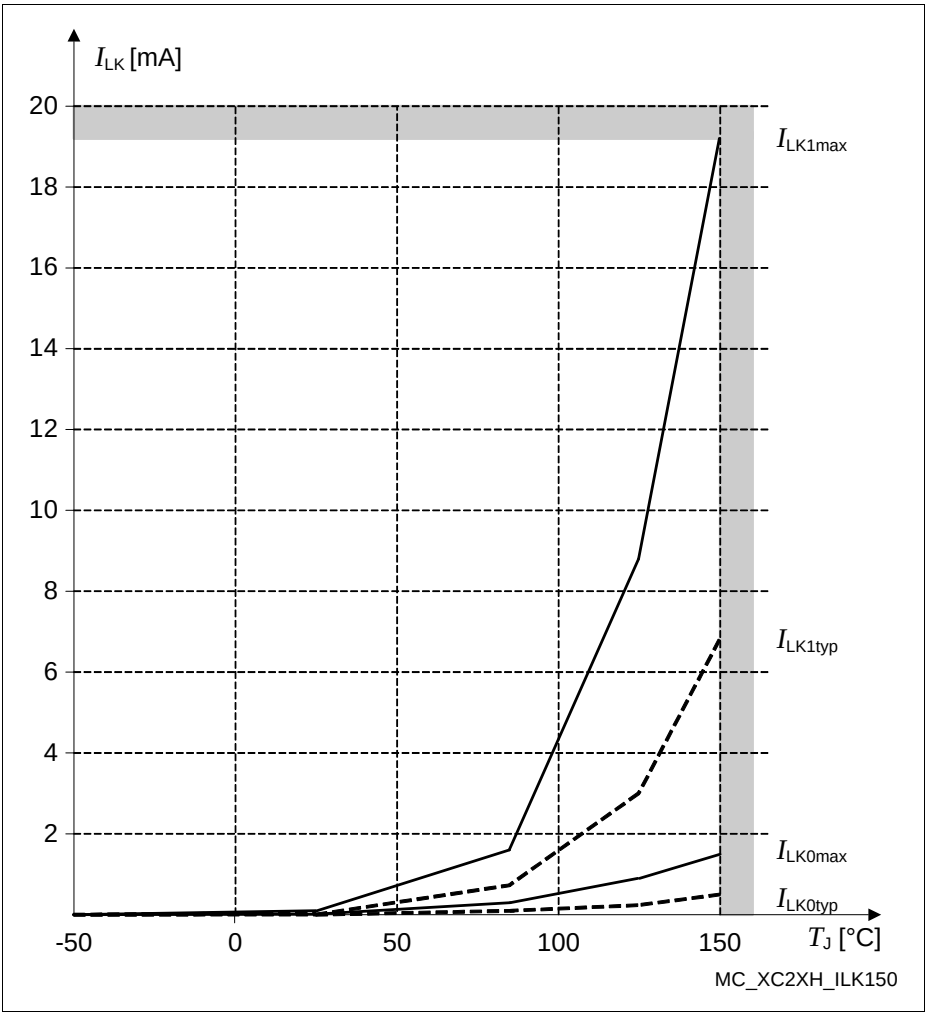

Figure 16 Leakage Supply Current as a Function of Temperature

4) TUE is tested at V_{AREF} = V_{DDPA} = 5.0 V, V_{AGND} = 0 V. It is verified by design for all other voltages within the defined voltage range. The specified TUE is valid only if the absolute sum of input overload currents on analog port pins (see I_{OV} specification) does not exceed 10 mA, and if V_{AREF} and V_{AGND} remain stable during the measurement time.

5) V_{AIN} may exceed V_{AGND} or V_{AREF} up to the absolute maximum ratings. However, the conversion result in these cases will be $X000_H$ or $X3FF_H$, respectively.

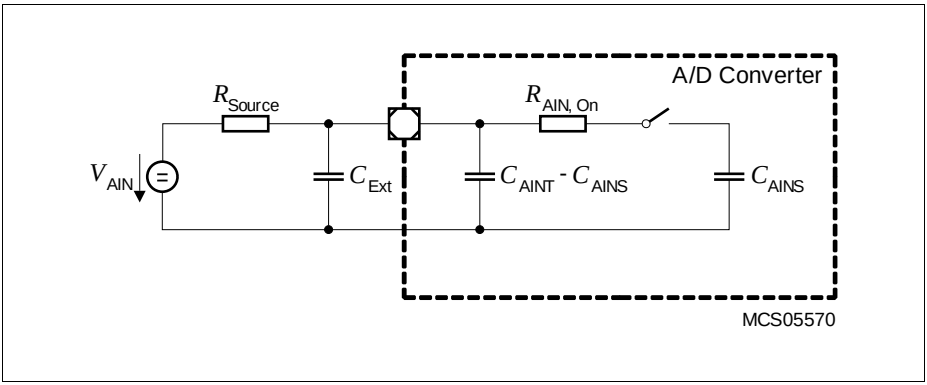

Figure 17 Equivalent Circuitry for Analog Inputs

Sample time and conversion time of the XC229[89]H's A/D converters are programmable. The timing above can be calculated using **Table 21**.
The limit values for f_{ADCI} must not be exceeded when selecting the prescaler value.

Table 21 A/D Converter Computation Table

GLOBCTR.5-0 (DIVA)	A/D Converter Analog Clock f_{ADCI}	INPCRx.7-0 (STC)	Sample Time[1] t_S
000000_B	f_{SYS}	00_H	$t_{ADCI} \times 2$
000001_B	f_{SYS} / 2	01_H	$t_{ADCI} \times 3$
000010_B	f_{SYS} / 3	02_H	$t_{ADCI} \times 4$
:	f_{SYS} / (DIVA+1)	:	$t_{ADCI} \times$ (STC+2)
111110_B	f_{SYS} / 63	FE_H	$t_{ADCI} \times 256$
111111_B	f_{SYS} / 64	FF_H	$t_{ADCI} \times 257$

1) The selected sample time is doubled if broken wire detection is active (due to the presampling phase).

Converter Timing Example A:

Assumptions: f_{SYS} = 100 MHz (i.e. t_{SYS} = 10 ns), DIVA = 03_H, STC = 00_H
Analog clock f_{ADCI} = f_{SYS} / 4 = 25 MHz, i.e. t_{ADCI} = 40 ns
Sample time t_S = $t_{ADCI} \times 2$ = 80 ns

Conversion 10-bit:

$t_{C10} = 13 \times t_{ADCI} + 2 \times t_{SYS} = 13 \times 40$ ns $+ 2 \times 10$ns = 0.540 µs

Conversion 8-bit:

$t_{C8} = 11 \times t_{ADCI} + 2 \times t_{SYS} = 11 \times 40$ ns $+ 2 \times 10$ ns = 0.460 µs

Converter Timing Example B:

Assumptions: f_{SYS} = 40 MHz (i.e. t_{SYS} = 25 ns), DIVA = 02_H, STC = 03_H
Analog clock f_{ADCI} = f_{SYS} / 3 = 13.3 MHz, i.e. t_{ADCI} = 75 ns
Sample time t_S = $t_{ADCI} \times 5$ = 375 ns

Conversion 10-bit:

$t_{C10} = 16 \times t_{ADCI} + 2 \times t_{SYS} = 16 \times 75$ ns $+ 2 \times 25$ ns = 1.25 µs

Conversion 8-bit:

$t_{C8} = 14 \times t_{ADCI} + 2 \times t_{SYS} = 14 \times 75$ ns $+ 2 \times 25$ ns = 1.10 µs

4.7.2 Definition of Internal Timing

The internal operation of the XC229[89]H is controlled by the internal system clock f_{SYS}.

Because the system clock signal f_{SYS} can be generated from a number of internal and external sources using different mechanisms, the duration of the system clock periods (TCSs) and their variation (as well as the derived external timing) depend on the mechanism used to generate f_{SYS}. This must be considered when calculating the timing for the XC229[89]H.

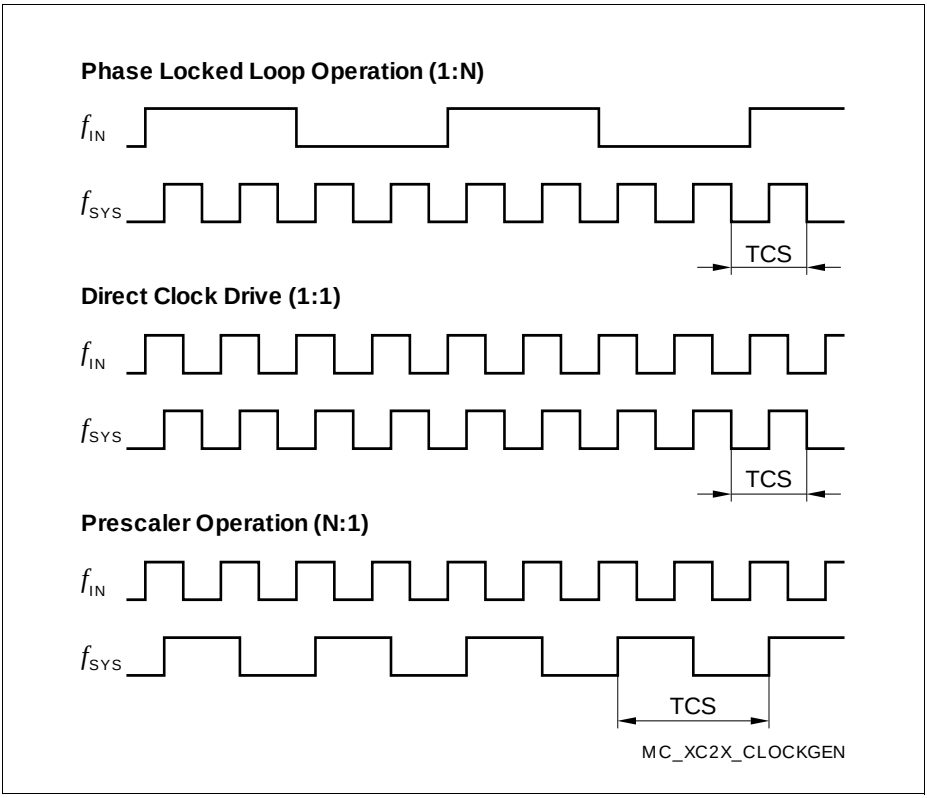

Figure 20 Generation Mechanisms for the System Clock

*Note: The example of PLL operation shown in **Figure 20** uses a PLL factor of 1:4; the example of prescaler operation uses a divider factor of 2:1.*

The specification of the external timing (AC Characteristics) depends on the period of the system clock (TCS).

1) The amplitude voltage V_{AX1} refers to the offset voltage V_{OFF}. This offset voltage must be stable during the operation and the resulting voltage peaks must remain within the limits defined by V_{IX1}.
2) Overload conditions must not occur on pin XTAL1.

Note: For crystal or ceramic resonator operation, it is strongly recommended to measure the oscillation allowance (negative resistance) in the final target system (layout) to determine the optimum parameters for oscillator operation.
The manufacturers of crystals and ceramic resonators offer an oscillator evaluation service. This evaluation checks the crystal/resonator specification limits to ensure a reliable oscillator operation.

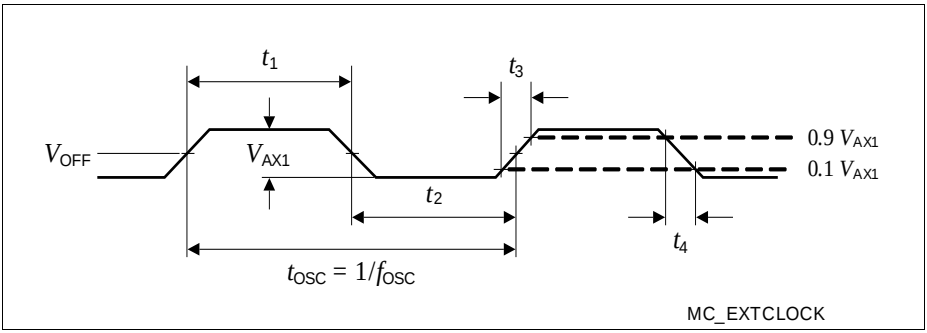

Figure 22 External Clock Drive XTAL1

4.7.5 External Bus Timing

The following parameters specify the behavior of the XC229[89]H bus interface.

Note: These parameters are not subject to production test but verified by design and/or characterization.

Note: Operating Conditions apply.

Table 31 Parameters

Parameter	Symbol	Values			Unit	Note / Test Condition
		Min.	Typ.	Max.		
CLKOUT Cycle Time[1)]	t_5 CC	–	1 / f_{SYS}	–	ns	
CLKOUT high time	t_6 CC	2	–	–		
CLKOUT low time	t_7 CC	2	–	–		
CLKOUT rise time	t_8 CC	–	–	3	ns	
CLKOUT fall time	t_9 CC	–	–	3		

1) The CLKOUT cycle time is influenced by PLL jitter. For longer periods the relative deviation decreases (see PLL deviation formula).

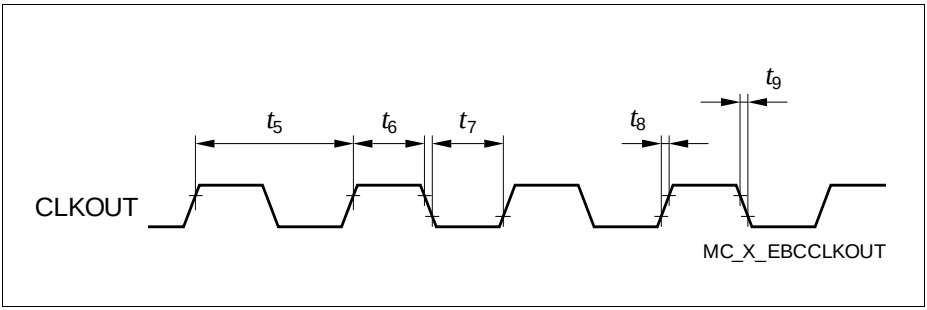

Figure 23 CLKOUT Signal Timing

Note: The term CLKOUT refers to the reference clock output signal which is generated by selecting f_{SYS} as the source signal for the clock output signal EXTCLK on pin P2.8 and by enabling the high-speed clock driver on this pin.

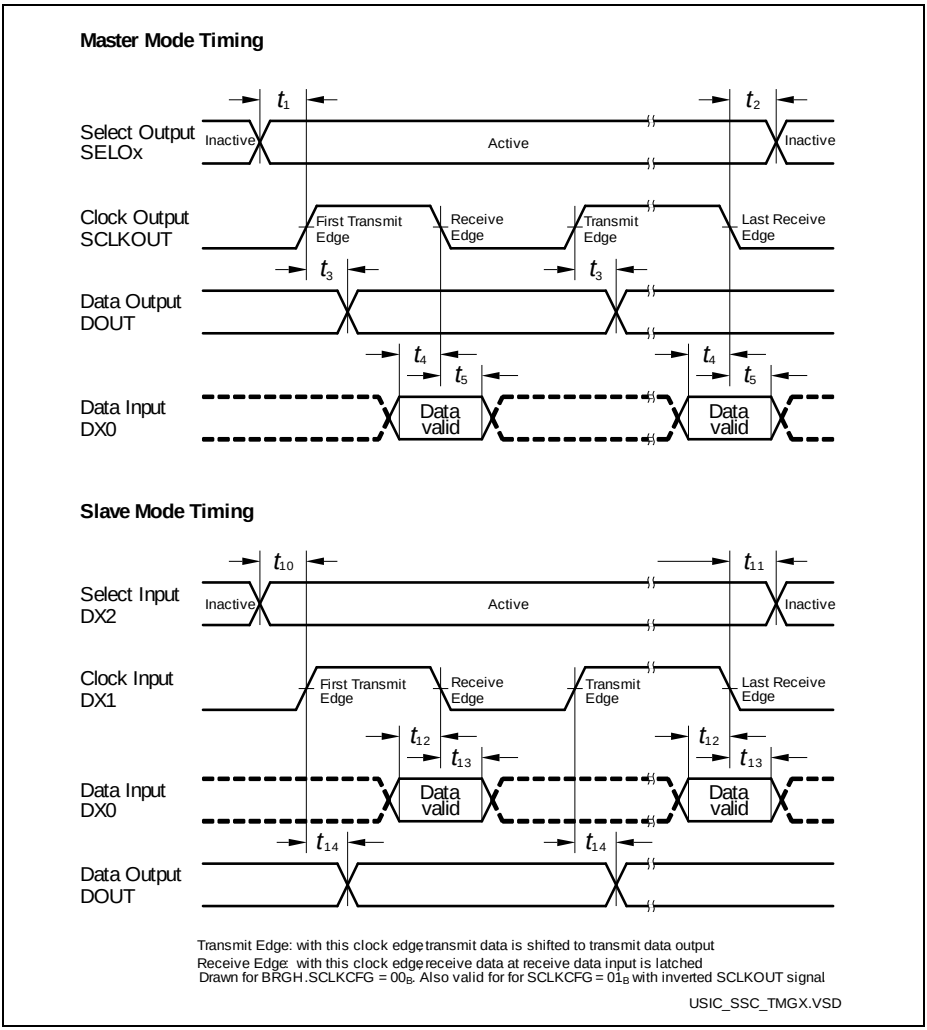

Figure 27 USIC - SSC Master/Slave Mode Timing

Note: This timing diagram shows a standard configuration where the slave select signal is low-active and the serial clock signal is not shifted and not inverted.

Table 42 JTAG Interface Timing for Upper Voltage Range (cont'd)

Parameter	Symbol	Values			Unit	Note / Test Condition
		Min.	Typ.	Max.		
TCK low time	t_3 SR	16	–	–	ns	
TCK clock rise time	t_4 SR	–	–	8	ns	
TCK clock fall time	t_5 SR	–	–	8	ns	
TDI/TMS setup to TCK rising edge	t_6 SR	6	–	–	ns	
TDI/TMS hold after TCK rising edge	t_7 SR	6	–	–	ns	
TDO valid from TCK falling edge (propagation delay)[2]	t_8 CC	–	25	29	ns	
TDO high impedance to valid output from TCK falling edge[3][2]	t_9 CC	–	25	29	ns	
TDO valid output to high impedance from TCK falling edge[2]	t_{10} CC	–	25	29	ns	
TDO hold after TCK falling edge[2]	t_{18} CC	5	–	–	ns	

1) Under typical conditions, the JTAG interface can operate at transfer rates up to 20 MHz.
2) The falling edge on TCK is used to generate the TDO timing.
3) The setup time for TDO is given implicitly by the TCK cycle time.

Table 43 is valid under the following conditions: C_L= 20 pF; voltage_range= lower

Table 43 JTAG Interface Timing for Lower Voltage Range

Parameter	Symbol	Values			Unit	Note / Test Condition
		Min.	Typ.	Max.		
TCK clock period	t_1 SR	50	–	–	ns	
TCK high time	t_2 SR	16	–	–	ns	
TCK low time	t_3 SR	16	–	–	ns	
TCK clock rise time	t_4 SR	–	–	8	ns	
TCK clock fall time	t_5 SR	–	–	8	ns	
TDI/TMS setup to TCK rising edge	t_6 SR	6	–	–	ns	

Table 43 JTAG Interface Timing for Lower Voltage Range (cont'd)

Parameter	Symbol	Values			Unit	Note / Test Condition
		Min.	Typ.	Max.		
TDI/TMS hold after TCK rising edge	t_7 SR	6	–	–	ns	
TDO valid from TCK falling edge (propagation delay)[1]	t_8 CC	–	32	36	ns	
TDO high impedance to valid output from TCK falling edge[2)1)]	t_9 CC	–	32	36	ns	
TDO valid output to high impedance from TCK falling edge[1]	t_{10} CC	–	32	36	ns	
TDO hold after TCK falling edge[1]	t_{18} CC	5	–	–	ns	

1) The falling edge on TCK is used to generate the TDO timing.

2) The setup time for TDO is given implicitly by the TCK cycle time.

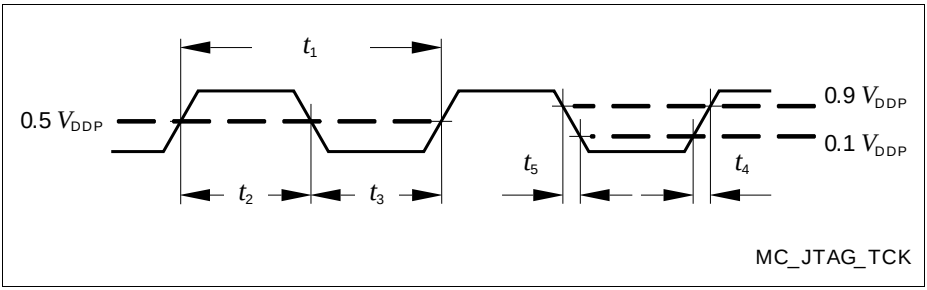

Figure 32 Test Clock Timing (TCK)